DATA SHEET



MOS FIELD EFFECT TRANSISTOR **3SK222**

RF AMPLIFIER FOR FM TUNER AND VHF TV TUNER N-CHANNEL SI DUAL GATE MOS FIELD-EFFECT TRANSISTOR 4 PINS MINI MOLD

FEATURES

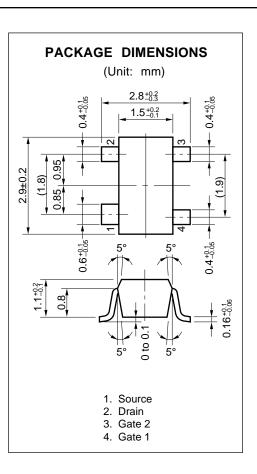
- The Characteristic of Cross-Modulation is good. CM = 92 dB μ TYP. @ f = 200 MHz, GR = -30 dB
- Low Noise Figure: NF1 = 1.2 dB TYP. (f = 200 MHz)
- High Power Gain:

NF2 = 1.0 dB TYP. (f = 55 MHz) GPs = 23 dB TYP. (f = 200 MHz)

- Enhancement Type.
- Suitable for use as RF amplifier in FM tuner and VHF TV tuner.
- Automatically Mounting: Embossed Type Taping
- Small Package: 4 Pins Mini Mold

ABSOLUTE MAXIMUM RATINGS (T_A = 25 $^{\circ}$ C)

| Drain to Source Voltage | VDSX | 18 | V |
|-------------------------|------------------|------------------------|----|
| Gate1 to Source Voltage | V _{G1S} | ±8 (±10) ^{*1} | V |
| Gate2 to Source Voltage | V _{G2S} | ±8 (±10) ^{*1} | V |
| Gate1 to Drain Voltage | Vg1d | 18 | V |
| Gate2 to Drain Voltage | Vg2d | 18 | V |
| Drain Current | lD | 25 | mA |
| Total Power Dissipation | PD | 200 | mW |
| Channel Temperature | Tch | 125 | °C |
| Storage Temperature | Tstg | -55 to +125 | °C |
| * 1 R∟ ≥ 10 kΩ | | | |



PRECAUTION

Avoid high static voltages or electric fields so that this device would not suffer from any damage due to those voltage or fields.

ELECTRICAL CHARACTERISTICS (TA = 25 $^{\circ}$ C)

| CHARACTERISTIC | SYMBOL | MIN. | TYP. | MAX. | UNIT | TEST CONDITIONS | |
|--------------------------------------|-------------------|------|------|------|------|--|--|
| Drain to Source Breakdown Voltage | BVdsx | 18 | | | V | $V_{G1S} = V_{G2S} = -2 V$, ID = 10 μ A | |
| Drain Current | Idsx | 0.01 | | 8.0 | mA | $V_{DS} = 6 V, V_{G2S} = 3 V, V_{G1S} = 0.75 V$ | |
| Gate1 to Source Cutoff Voltage | VG1S(off) | 0 | | +1.0 | V | $V_{\text{DS}} = 6 \text{ V}, \text{ V}_{\text{G2S}} = 3 \text{ V}, \text{ Id} = 10 \mu\text{A}$ | |
| Gate2 to Source Cutoff Voltage | VG2S(off) | 0 | | +1.0 | V | $V_{DS} = 6 V$, $V_{G2S} = 3 V$, $I_D = 10 \mu A$ | |
| Gate1 Reverse Current | I _{G1SS} | | | ±20 | nA | $V_{DS} = 0, V_{G2S} = 0, V_{G1S} = \pm 8 V$ | |
| Gate2 Reverse Current | Ig2ss | | | ±20 | nA | $V_{DS} = 0, V_{G1S} = 0, V_{G2S} = \pm 8 V$ | |
| Forward Transfer Admittance | y _{fs} | 15 | 19.5 | | mS | $V_{DS} = 5 V$, $V_{G2S} = 4 V$, $I_D = 10 mA$ f = 1 kHz | |
| Input Capacitance | Ciss | 3.6 | 4.3 | 5.0 | pF | $V_{DS} = 6 V, V_{G2S} = 3 V, I_D = 10 mA$ f = 1 MHz | |
| Output Capacitance | CDSS | 1.0 | 1.5 | 2.0 | pF | | |
| Reverse Transfer Capacitance | Crss | | 0.02 | 0.03 | pF | | |
| Power Gain | Gps | 21.0 | 23.0 | | dB | $V_{DS} = 6 V, V_{G2S} = 4 V, I_D = 10 mA$ | |
| Noise Figure 1 | NF1 | | 1.2 | 2.0 | dB | f = 200 MHz | |
| Noise Figure 2 | NF2 | | 1.0 | 2.0 | dB | $V_{DS} = 6 V, V_{G2S} = 4 V, I_D = 10 mA$ f = 55 MHz | |

IDSX Classification

| Class | V21/VBA* | V22/VBB* | |
|-----------|-------------|------------|--|
| Marking | V21 | V22 | |
| Ibsx (mA) | 0.01 to 3.0 | 1.0 to 8.0 | |

* Old specification/New specification

1 V

1

6

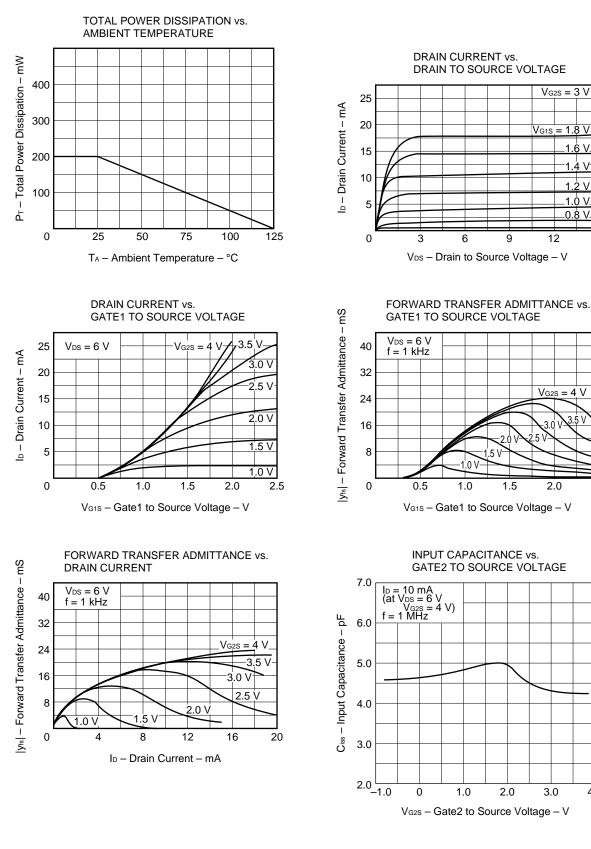
1.0 V

0.8 V-

-0.6 V

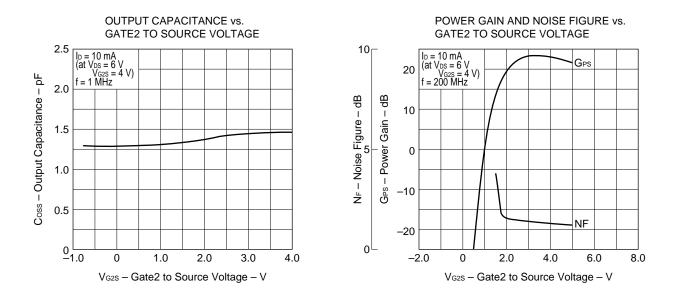
15

2.5

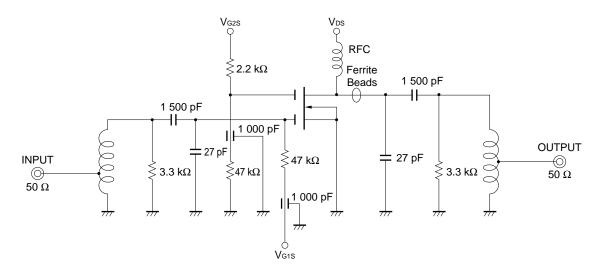


TYPICAL CHARACTERISTICS ($T_A = 25 \ ^{\circ}C$)

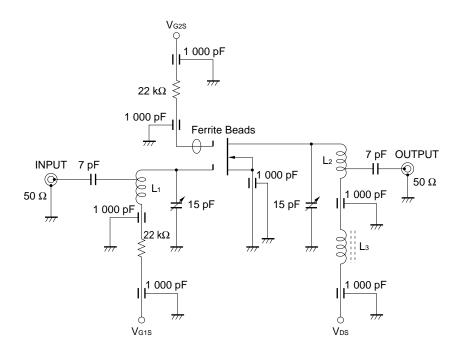
4.0



NF TEST CIRCUIT AT f = 55 MHz



GPS AND NF TEST CIRCUIT AT f = 200 MHz



L1: ϕ 0.6 mm U.E.W ϕ 7 mm 3 T L2: ϕ 0.6 mm U.E.W ϕ 7 mm 3 T L3: RFC 2.2 μ H No part of this document may be copied or reproduced in any form or by any means without the prior written consent of NEC Corporation. NEC Corporation assumes no responsibility for any errors which may appear in this document.

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Anti-radioactive design is not implemented in this product.

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